



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2829
Examiner: Jermele M. Hollington

In Re PATENT APPLICATION OF:

Applicant(s) : Mikio OHTAKI
Serial No. : 09/904,663
Filed : July 16, 2001
For : SEMICONDUCTOR DEVICE
TEST METHOD
Attorney Ref. : KAN 120 D1

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) **INFORMATION DISCLOSURE**
) **STATEMENT**
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Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This is an information disclosure statement submitted in compliance with the timing requirements of 37 C.F.R. §1.97(c), i.e., after a first Office Action on the merits but before Final Rejection and/or Notice of Allowance. Pursuant to 37 C.F.R. § 1.97(e)(1), it is certified that each item submitted with this Information Disclosure Statement was first cited in an Office Action from the Japanese Patent Office in a counterpart foreign application on June 24, 2003, that is, less than three months prior to filing this Information Disclosure Statement.

Attached are a copy of a Japanese Office Action and three Japanese Patents with English translations. The relevance of the publications can be gleaned from the attached English language Abstracts. The documents are listed on the attached Form PTO-1449.

Consideration of the submitted documents is respectfully requested.

Respectfully submitted,

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August 20, 2003
Date

GA:tlc



FORM PTO-1449

INFORMATION DISCLOSURE STATEMENT

Atty. Docket

KAN 120 D1

Application No.

09/904,663

Applicant

Mikio OHTAKI

Filing Date

July 16, 2001

Group

2829

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub-Class	Translation
	AI	10-189670	7/21/98	JAPAN			Abstract
	AJ	11-17076	1/22/99	JAPAN			Abstract
	AK	64-001252	1/5/89	JAPAN			Abstract
	AL						
	AM						
	AN						

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

	AO	
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Examiner

Date Considered

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.